

ON Semiconductor®

FDD4685-F085

P-Channel PowerTrench® MOSFET

-40 V, -32 A, 35 mΩ

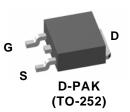
Features

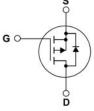
- \blacksquare Typical R_{DS(on)} = 23 m Ω at V_{GS} = -10V, I_D = -8.4 A
- Typical $R_{DS(on)}$ = 30 m Ω at V_{GS} = -4.5V, I_D = -7 A
- Typical $Q_{q(tot)}$ = 19 nC at V_{GS} = -5V, I_D = -8.4 A
- UIS Capability
- RoHS Compliant
- Qualified to AEC Q101

Applications

- Inverter
- Power Supplies







MOSFET Maximum Ratings T_J = 25°C unless otherwise noted.

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-to-Source Voltage		-40	V
V _{GS}	Gate-to-Source Voltage		±20	V
	Drain Current - Continuous (T _C < 90°C, V _{GS} =10) (No	ote 1)	-32	^
ID	Pulsed Drain Current		See Figure 4	A
E _{AS}	Single Pulse Avalanche Energy (N	ote 2)	121	mJ
_	Power Dissipation		83	W
P_D	Derate Above 25°C		0.56	W/°C
T _J , T _{STG}	Operating and Storage Temperature		-55 to + 175	°C
$R_{\theta JC}$	Thermal Resistance, Junction to Case		1.8	°C/W
$R_{\theta JA}$	Maximum Thermal Resistance, Junction to Ambient (N	ote 3)	40	°C/W

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDD4685	FDD4685-F085	D-PAK(TO-252)	13"	12mm	2500units

Notes:

- 1. Current is limited by bondwire configuration.
- Starting T_J = 25°C, L = 3mH, I_{AS} = 9A, V_{DD} = 40V during inductor charging and V_{DD} = 0V during time in avalanche.
 R_{0,JA} is the sum of the junction-to-case and case-to-ambient thermal resistance, where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design, while $R_{\theta JA}$ is determined by the board design. The maximum rating
- presented here is based on mounting on a 1 in² pad of 2oz copper.

 4. A suffix as "...F085P" has been temporarily introduced in order to manage a double source strategy as ON Semiconductor has officially announced in Aug 2014.

Units

Max.

Тур.

Electrical Characteristics	T ₁ = 25°C unless otherwise noted.
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Parameter

Off Characteristics							
B _{VDSS}	Drain-to-Source Breakdown Voltage	$I_D = -250 \mu A, V_{GS} = 0 V$	-40	-	-	V	
$\frac{\Delta B_{VDSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	ID = -250μA, referenced to 25°C	-	-33	-	mV/°C	
I _{DSS}	Drain-to-Source Leakage Current	V _{DS} = -32V	-	-	-1	μА	
I_{GSS}	Gate-to-Source Leakage Current	V _{GS} = ±20V	-	-	±100	nA	

Test Conditions

Min.

On Characteristics

Symbol

V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = -250 \mu A$	-1	-1.6	-3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	ID = –250μA, referenced to 25°C	-	4.9	-	mV/°C
R _{DS(on)}		I _D = -8.4A, V _{GS} = -10V	-	23	27	
	Drain to Source On Resistance	I _D = -7A, V _{GS} = -4.5V	-	30	35	mΩ
		$I_D = -8.4A, V_{GS} = -10V, T_J = 150^{\circ}C$	-	38	45	
9 _{FS}	Forward Transconductance	ID = -8.4A, VDS = -5V	-	23	-	S

Dynamic Characteristics

C _{iss}	Input Capacitance	V - 20V V - 0V	-	1790	2380	pF
Coss	Output Capacitance	$V_{DS} = -20V, V_{GS} = 0V,$ f = 1MHz	-	260	345	pF
C _{rss}	Reverse Transfer Capacitance	1 - 11VII 12	-	140	205	pF
R_g	Gate Resistance	f = 1MHz	-	4	-	Ω
Q _{g(ToT)}	Total Gate Charge	V 00V V 5V	-	19	27	nC
Q _{gs}	Gate-to-Source Gate Charge	$V_{DD} = -20V, V_{GS} = -5V,$ $I_{D} = -8.4A$	-	5.6	-	nC
Q_{gd}	Gate-to-Drain "Miller" Charge	1D0.4A	-	6.1	-	nC

Switching Characteristics

t _{d(on)}	Turn-On Delay		-	8	16	ns
t _r	Rise Time	V _{DD} = -20V, I _D = -8.4A,	-	15	27	ns
t _{d(off)}	Turn-Off Delay	V_{GS} = -10V, R_{GEN} = 6Ω	-	34	55	ns
t _f	Fall Time		1	14	26	ns

Drain-Source Diode Characteristics

V_{SD}	Source-to-Drain Diode Voltage	$I_{SD} = -8.4A, V_{GS} = 0V$	-	-0.85	-1.2	V
t _{rr}	Reverse-Recovery Time	1 - 9.4A dl /dt = 100A/vo	-	30	45	ns
Q_{rr}	Reverse-Recovery Charge	$I_{SD} = -8.4A$, $dI_{SD}/dt = 100A/\mu s$	-	31	47	nC

Typical Characteristics

0.0

25

50

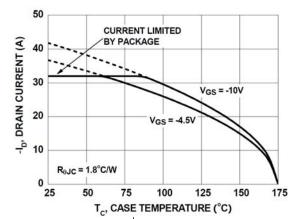


Figure 1. Normalized Power Dissipation vs. Case Temperature

T_C, CASE TEMPERATURE(°C)

75

100

125

150

Figure 2. Maximum Continuous Drain Current vs.
Case Temperature

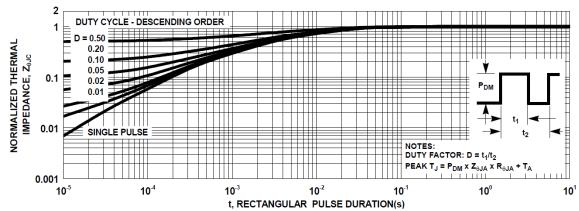


Figure 3. Normalized Maximum Transient Thermal Impedance

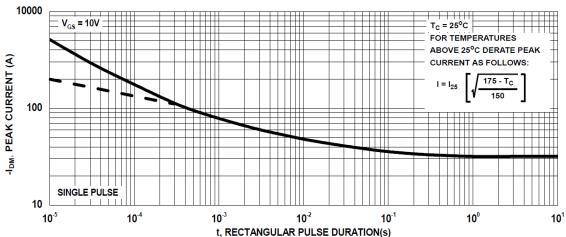


Figure 4. Peak Current Capability

Typical Characteristics

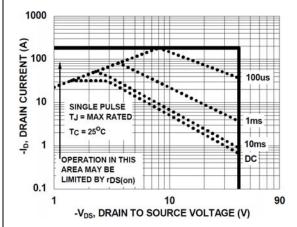
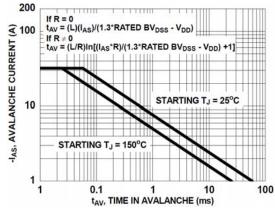


Figure 5. Forward Bias Safe Operating Area



NOTE: Refer to ON SemiconductorApplication Notes AN7514 and AN7515

Figure 6. Unclamped Inductive Switching Capability

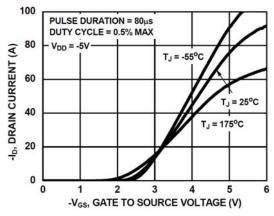


Figure 7. Transfer Characteristics

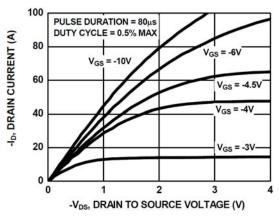


Figure 8. Saturation Characteristics

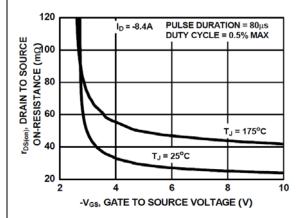


Figure 9. Drain to Source On-Resistance Variation vs. Gate to Source Voltage

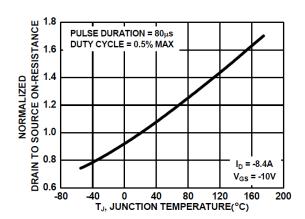


Figure 10. Normalized Drain to Source On Resistance vs. Junction Temperature

Typical Characteristics

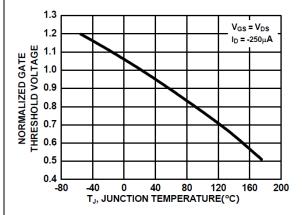


Figure 11. Normalized Gate Threshold Voltage vs.
Junction Temperature

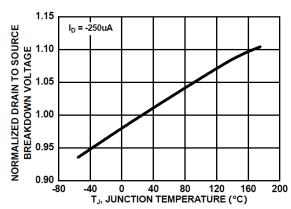


Figure 12. Normalized Drain to Source Breakdown Voltage vs. Junction Temperature

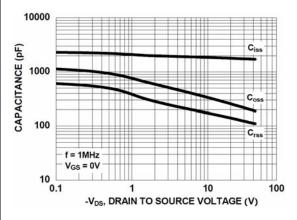


Figure 13. Capacitance vs. Drain to Source Voltage

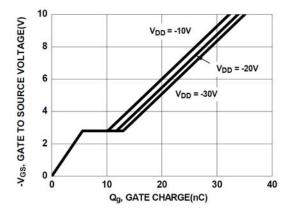


Figure 14. Gate charge vs. Gate to Source Voltage

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